

00862.023140

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent of:)	
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Takeshi YAMAMOTO et al.)	Examiner: A. Allawi
	:	
Application No.: 10/626,744)	Group Art Unit: 2877
	:	
Filed: July 25, 2003)	Confirmation No.: 9697
	:	
For: OPTICAL APPARATUS, MEASUREMENT)	March 2, 2007
METHOD, AND SEMICONDUCTOR DEVICE	:	
MANUFACTURING METHOD)	
	:	
U.S. Patent No. 7,084,982 B2)	
	:	
Issued: August 1, 2006)	

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450
Attention: Certificate of Correction Branch

LETTER CALLING ATTENTION TO ERRORS IN PATENT

Sir:

Patentees note the following errors in the above-identified patent:

IN THE DRAWINGS:

Sheet 8, in "FIG. 8," in the lower right-hand legend, "THICKNESSMETER" should read -- THICKNESS METER --.

COLUMN 5:

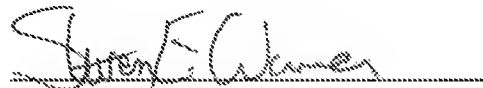
Line 51, "First Embodiments" should read -- First Embodiment --.

These errors are relatively insignificant. Therefore, Patentees believe that filing a Request for Certificate of Correction is not warranted. Rather, Patentees request that this paper be placed of record in the official file of the subject patent.

Patentees believe no fee is due for filing this paper. Nevertheless, the Commissioner is authorized to charge Deposit Account No. 06-1205 should any fee be deemed required.

Patentees' undersigned attorney may be reached in our Washington, D.C. Office by telephone at (202) 530-1010. All correspondence should continue to be directed to our below-listed address.

Respectfully submitted,

A handwritten signature in dark ink, appearing to read "Steven E. Warner", is written over a horizontal dotted line.

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